	Application No.	Applicant(s)	
Notice of Allowability	10/043,723	. MAEKAWA ET AL.	
	Examiner	Art Unit	
	Jennifer M. Dolan	2813	
The MAILING DATE of this communication app All claims being allowable, PROSECUTION ON THE MERITS IS herewith (or previously mailed), a Notice of Allowance (PTOL-85 NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT F of the Office or upon petition by the applicant. See 37 CFR 1.31	S (OR REMAINS) CLOSED	in this application. If not includ	ed
<ol> <li>This communication is responsive to <u>the 11/10/03 Amdt.</u></li> <li>The allowed claim(s) is/are <u>52-58</u>; 71-74.</li> </ol>			
<ul> <li>3.  The drawings filed on <u>08 March 2002</u> are accepted by the</li> </ul>	- F		
<ul> <li>4. Acknowledgment is made of a claim for foreign priority un</li> </ul>		40	
a) ☐ All b) ☐ Some* c) ☐ None of the:	ider 35 U.S.C. § 119(a)-(a)	or (†).	
<ol> <li>Certified copies of the priority documents hav</li> </ol>	e been received.		
2.  Certified copies of the priority documents hav	e been received in Applica	tion No	
<ol> <li>Copies of the certified copies of the priority do International Bureau (PCT Rule 17.2(a)).</li> </ol>			tion from the
* Certified copies not received:			
5. Acknowledgment is made of a claim for domestic priority under 35 U.S.C. § 119(e) (to a provisional application).			
(a) The translation of the foreign language provisional application has been received.			
6. Acknowledgment is made of a claim for domestic priority L	under 35 U.S.C. §§ 120 and	1/or 121.	
Applicant has THREE MONTHS FROM THE "MAILING DATE" of below. Failure to timely comply will result in ABANDONMENT of	this application. THIS TH	REE-MONTH PERIOD IS NOT	EXTENDABLE.
7. A SUBSTITUTE OATH OR DECLARATION must be subr INFORMAL PATENT APPLICATION (PTO-152) which gives reasonable to the subration of the subratio	mitted. Note the attached E son(s) why the oath or decl	XAMINER'S AMENDMENT or Naration is deficient.	NOTICE OF
<ul> <li>8. ☐ CORRECTED DRAWINGS must be submitted.</li> <li>(a) ☐ including changes required by the Notice of Draftsper</li> <li>1) ☐ hereto or 2) ☐ to Paper No</li> <li>(b) ☐ including the size of the state of the s</li></ul>			
(b) including changes required by the proposed drawing	correction filed, wh	ich has been approved by the E	xaminer.
(c) including changes required by the attached Examiner	r's Amendment / Comment	or in the Office action of Paper	No
Identifying indicia such as the application number (see 37 CFR 1 each sheet.	1.84(c)) should be written on	the drawings in the front (not the	back) of
<ol> <li>DEPOSIT OF and/or INFORMATION about the depo- attached Examiner's comment regarding REQUIREMENT FOR T</li> </ol>	osit of BIOLOGICAL MAT THE DEPOSIT OF BIOLOG	FERIAL must be submitted. N BICAL MATERIAL.	Note the
Attachment(s)			
<ul> <li>1⊠ Notice of References Cited (PTO-892)</li> <li>3□ Notice of Draftperson's Patent Drawing Review (PTO-948)</li> <li>5□ Information Disclosure Statements (PTO-1449), Paper No</li> <li>7□ Examiner's Comment Regarding Requirement for Deposit of Biological Material</li> </ul>	4☐ Intervie 6☐ Examir	of Informal Patent Application (Few Summary (PTO-413), Paper ner's Amendment/Comment ner's Statement of Reasons for A	No
o. Diological material	a Cruei	Paul Shitchea	dk
	S	CARL WHITEHEAD, JA. SUPERVISORY PATENT EXAMINED	<b>)</b>

U.S. Patent and Trademark Office PTOL-37 (Rev. 04-03 Art Unit: 2813

## DETAILED ACTION

## Allowable Subject Matter

- 1. Claims 52-58 and 71-74 are allowed.
- 2. The following is an examiner's statement of reasons for allowance: The primary reason for allowance is the inclusion of an insulator film deposited between an amorphous silicon layer and a transition metal layer, the insulator film dimensioned appropriately such that the amorphous film can be doped with transition metal nuclei through the insulating film. The examiner notes that the product-by-process limitations in the independent claims are only given weight to the extent that they affect the final product; nevertheless, it is clear that the claims require a TFT structure having a silicon film comprising amorphous silicon regions and transition metal-doped single-grain regions, a thin insulating layer directly covering at least the single-grain regions, such that doping could occur through the insulating layer, and a transition metal layer directly on top of the insulating layer.

The prior art teaches two general configurations: placing the transition metal directly on the amorphous silicon layer, and then recrystallizing; and forming an insulating layer on the amorphous layer, forming a window completely through the insulating layer, and then forming a transition metal layer upon the insulating layer, such that doping occurs through the window, where the transition metal directly touches the amorphous silicon film. There is no suggestion in the prior art that it would in any way be advantageous or facilitate the formation of single grain material to position an insulating layer such that the transition metal must diffuse through the insulating material. Since the present invention uses the insulating layer for the specific purpose

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of controlling the transition metal doping, and since it is generally difficult to obtain large singlegrain regions from transition metal doping, it is the examiner's opinion that the inclusion of a thin insulating layer would not have been obvious to one skilled in the art.

Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

## Conclusion

3. The prior art made of record and not relied upon is considered pertinent to applicant's disclosure.

U.S. Patent No. 6,162,667 to Funai et al. discloses diffusion of a transition metal into an amorphous silicon layer through a thin insulating film. There is no suggestion, however, that such a process leads to the production of large single grain regions or that an insulating layer would be advantageous to use with a transition metal, as opposed to a metal containing solvent, as in Funai. Additionally, as Funai et al does not constitute valid prior art under 35 U.S.C. 103 (a) based upon 102 (e), due to the common assignee.

Any inquiry concerning this communication or earlier communications from the examiner should be directed to Jennifer M. Dolan whose telephone number is (703) 305-3233 Art Unit: 2813

until 2/9/04, and (571) 272-1690 thereafter. The examiner can normally be reached on Monday-Friday 8:30am-5:00pm.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Carl W. Whitehead, Jr. can be reached on (703) 308-4940. The fax phone number for the organization where this application or proceeding is assigned is (703) 872-9306.

Any inquiry of a general nature or relating to the status of this application or proceeding should be directed to the receptionist whose telephone number is (703) 308-0956.

Jennifer M. Dolan Examiner Art Unit 2813

jmd